
**Surface chemical analysis —
Secondary ion mass spectrometry —
Linearity of intensity scale in single
ion counting time-of-flight mass
analysers**

Analyse chimique des surfaces — Spectrométrie de masse des ions secondaires — Linéarité de l'échelle d'intensité des analyseurs de masse à temps de vol pour comptage des ions individuels





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Contents

	Page
Foreword	iv
Introduction	v
1 Scope	1
2 Symbols and abbreviations	1
2.1 Abbreviated terms	1
2.2 Symbols	1
3 Outline of method	2
4 Procedure for evaluating the intensity linearity	5
4.1 Obtaining the reference sample	5
4.2 Preparation for mounting the sample.....	5
4.3 Mounting the sample.....	5
4.4 Operating the instrument.....	6
4.5 Acquiring the data.....	8
4.6 Checking the linearity.....	12
5 Interval for repeat measurements	17
Annex A (normative) Computation of raster size, ion beam current, number of frames for analysis, and counts per pulse	18
Annex B (normative) Charge compensation setting	20
Annex C (normative) Ion detector setting	21
Annex D (informative) Instrumental factors affecting linearity	23
Bibliography	25